

## Description

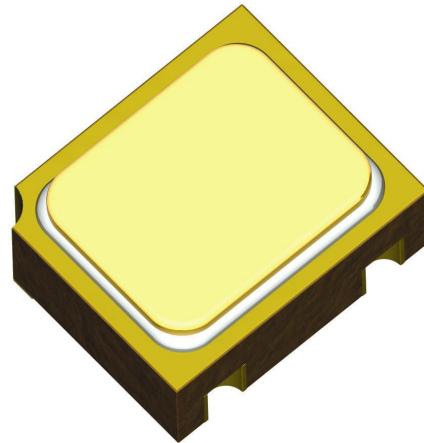
Semicoa Semiconductors offers:

- Screening and processing per MIL-PRF-19500 Appendix E
- JAN level (2N5109UBJ)
- JANTX level (2N5109UBJX)
- JANTXV level (2N5109UBJV)
- JANS level (2N5109UBJS)
- QCI to the applicable level
- 100% die visual inspection per MIL-STD-750 method 2072 for JANTXV and JANS
- Radiation testing (total dose) upon request

Please contact Semicoa for special configurations  
[www.SEMICOA.com](http://www.SEMICOA.com) or (714) 979-1900

## Applications

- General purpose
- VHF-UHF amplifier transistor
- NPN silicon transistor



## Features

- Hermetically sealed Cersot ceramic
- Also available in chip configuration
- Chip geometry 1009
- Reference document: MIL-PRF-19500/453

## Benefits

- Qualification Levels: JAN, JANTX, JANTXV and JANS
- Radiation testing available

Absolute Maximum Ratings		$T_c = 25^\circ\text{C}$ unless otherwise specified	
Parameter	Symbol	Rating	Unit
Collector-Emitter Voltage	$V_{CEO}$	20	Volts
Collector-Base Voltage	$V_{CBO}$	40	Volts
Emitter-Base Voltage	$V_{EBO}$	3	Volts
Collector Current, Continuous	$I_C$	400	mA
Power Dissipation, $T_A = 25^\circ\text{C}$ Derate linearly above $25^\circ\text{C}$	$P_T$	1 5.71	W mW/ $^\circ\text{C}$
Power Dissipation, $T_c = 25^\circ\text{C}$ Derate linearly above $25^\circ\text{C}$	$P_T$	2.9 16.6	W mW/ $^\circ\text{C}$
Thermal Resistance	$R_{\theta JA}$	175	$^\circ\text{C}/\text{W}$
Operating Junction Temperature	$T_J$	-65 to +200	$^\circ\text{C}$
Storage Temperature	$T_{STG}$	-65 to +200	$^\circ\text{C}$

**ELECTRICAL CHARACTERISTICS**

 characteristics specified at  $T_A = 25^\circ\text{C}$ 

<b>Off Characteristics</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Test Conditions</b>	<b>Min</b>	<b>Typ</b>	<b>Max</b>	<b>Units</b>
Collector-Base Breakdown Voltage	$V_{(\text{BR})\text{CBO}}$	$I_C = 100 \mu\text{A}$	40			Volts
Collector-Emitter Breakdown Voltage	$V_{(\text{BR})\text{CEO}}$	$I_C = 5 \text{ mA}$	20			Volts
Collector-Emitter Breakdown Voltage	$V_{(\text{BR})\text{CER}}$	$I_C = 5 \text{ mA}, R_{BE} = 10 \Omega$	40			Volts
Emitter-Base Breakdown Voltage	$V_{(\text{BR})\text{EBO}}$	$I_E = 100 \mu\text{A}$	3			Volts
Collector-Emitter Cutoff Current	$I_{\text{CEO}1}$ $I_{\text{CEO}2}$	$V_{CE} = 15 \text{ Volts}$ $V_{CE} = 15 \text{ Volts}, T_A = 175^\circ\text{C}$			20 5	$\mu\text{A}$ $\text{mA}$

<b>On Characteristics</b>		Pulse Test: Pulse Width = 300 $\mu\text{s}$ , Duty Cycle $\leq 2.0\%$				
<b>Parameter</b>	<b>Symbol</b>	<b>Test Conditions</b>	<b>Min</b>	<b>Typ</b>	<b>Max</b>	<b>Units</b>
DC Current Gain	$h_{FE1}$ $h_{FE2}$	$I_C = 50 \text{ mA}, V_{CE} = 15 \text{ Volts}$ $I_C = 50 \text{ mA}, V_{CE} = 5 \text{ Volts}$ $T_A = -55^\circ\text{C}$	40 15		150	
Collector-Emitter Saturation Voltage	$V_{CE\text{sat}}$	$I_C = 100 \text{ mA}, I_B = 10 \text{ mA}$			0.5	Volts

<b>Dynamic Characteristics</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Test Conditions</b>	<b>Min</b>	<b>Typ</b>	<b>Max</b>	<b>Units</b>
Magnitude – Common Emitter, Short Circuit Forward Current Transfer Ratio	$ h_{FE1} $ $ h_{FE2} $ $ h_{FE3} $	$V_{CE} = 15 \text{ Volts}, f = 200 \text{ MHz}$ , $I_C = 25 \text{ mA}$ $I_C = 50 \text{ mA}$ $I_C = 100 \text{ mA}$	5 6 5		10.0 11.0 10.5	
Open Circuit Output Capacitance	$C_{\text{OBO}}$	$V_{CB} = 5 \text{ Volts}, I_E = 0 \text{ mA}$ , $100 \text{ kHz} < f < 1 \text{ MHz}$			3.5	pF
Power Gain (narrow band) current	$G_{PE}$	$V_{CC} = 15 \text{ Volts}, I_C = 50 \text{ mA}$ , $f = 200 \text{ MHz}, P_{in} = -10 \text{ dB}$	11			dB
Cross Modulation	$cm$	$V_{CC} = 15 \text{ Volts}, I_C = 50 \text{ mA}$ , 54 dB output			-57	dB
Noise Figure	NF	$V_{CC} = 15 \text{ Volts}, I_C = 10 \text{ mA}$ , $f = 200 \text{ MHz}, P_{in} = -10 \text{ dB}$			3.5	dB
Voltage Gain (wideband)	G	$V_{CC} = 15 \text{ Volts}, I_C = 50 \text{ mA}$ , $50 \text{ MHz} < f < 216 \text{ MHz}$ , $P_{in} = -10 \text{ dB}$	11			dB